

RFID 13.56 MHz Radio Test Report FCC ID: ORK-TC63CUT021

This report concerns (check one) : ⊠ Original Grant ☐ Class II Change

Issued Date : May. 28, 2013 Project No. : 1305C074

Equipment: NFC Reader Writer Product **Model Name**: TC63CUT021; VA-A40NFCT-A

Applicant: Toppan Forms Co. Ltd

Address : 1-7-3 Higashi Shimbashi, Minato-Ku, Tokyo

105-8311, Japan

Manufacturer: Toppan Forms Co. Ltd

Address: 1-7-3 Higashi Shimbashi, Minato-Ku, Tokyo

105-8311, Japan

Tested by: Neutron Engineering Inc. EMC Laboratory

Date of Receipt: May. 13, 2013

Date of Test:

May. 13, 2013 ~ May. 27, 2013

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Declaration

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Limitation

For the use of the authority's logo is limited unless the Test Standard(s)/Scope(s)/Item(s) mentioned in this test report is (are) included in the conformity assessment authorities acceptance respective.

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1 CERTIFICATION

Equipment : NFC Reader Writer Product

Brand Name: TOPPAN FORMS Casio

Model Name: TC63CUT021 VA-A40NFCT-A

Applicant : Toppan Forms Co. Ltd
Factory : AddPlus Electronic Pte Ltd

Address : Block 35 Marsiling Industrial Estate Road 3, #04-06, Singapore 739257

Date of Test : May. 13, 2013 ~ May. 27, 2013 Test Item : ENGINEERING SAMPLE

Standards : FCC Part 15, Subpart C: 15.225

ANSI C63.4: 2009

The above equipment has been tested and found compliance with the requirement of the relative standards by Neutron Engineering Inc. EMC Laboratory.

The test data, data evaluation, and equipment configuration contained in our test report (Ref No. NEI-FCCP-1-1305C074) were obtained utilizing the test procedures, test instruments, test sites that has been accredited by the Authority of TAF according to the ISO-17025 quality assessment standard and technical standard(s).

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2 SUMMARY OF TEST RESULTS

Test procedures according to the technical standards:

FCC Part 15, Subpart C: 15.225						
Standard Section Test Item			Remark			
15.207	Conducted emission	PASS				
15.35 / 15.205 / 15.209 / Radiated emission		PASS				
15.225(e) Frequency Stability		PASS				
15.203 Antenna Requirement		PASS				
-	20dB Occupied Bandwidth Measurement	PASS				

NOTE:

(1) "N/A" denotes test is not applicable in this Test Report.

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2.1 TEST FACILITY

The test facilities used to collect the test data in this report is **DG-C02/DG-CB03** at the location of No.3, Jinshagang 1st Road, ShiXia, Dalang Town, Dong Guan, China.523792 Neutron's test firm number is 319330

2.2 MEASUREMENT UNCERTAINTY

The measurement uncertainty is not specified by FCC rules and for reference only.

The reported uncertainty of measurement $\mathbf{y} \pm \mathbf{U}$, where expended uncertainty \mathbf{U} is based on a standard uncertainty multiplied by a coverage factor of $\mathbf{k=2}$, providing a level of confidence of approximately 95%.

The measurement instrumentation uncertainty considerations contained in CISPR 16-4-2.

A. Conducted Measurement:

Test Site	Method	d Measurement Frequency Range		NOTE
DG-C02	CISPR	150 KHz ~ 30MHz	1.94	

B. Radiated Measurement:

Test Site Method		Measurement Frequency Range	ncy Ant. H / V U , (dB)		NOTE
		9K~30MHz	V	3.79	
		9K~30MHz	Н	3.57	
		30MHz ~ 200MHz	V	3.82	
	CISPR	30MHz ~ 200MHz	Η	3.60	
DG-CB03		200MHz ~ 1,000MHz	V	3.86	
DG-CB03		200MHz ~ 1,000MHz	Н	3.94	
		1GHz~18GHz	V	3.12	
		1GHz~18GHz	Н	3.68	
		18GHz~40GHz	V	4.15	
		18GHz~40GHz	Н	4.14	

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3 GENERAL INFORMATION

3.1 GENERAL DESCRIPTION OF EUT

Equipment	NFC Reader Writer Product			
Brand Name	TOPPAN FORMS			
Model Name	TC63CUT021			
OEM Brand/Model Name	Casio/ VA-A40NFCT-A			
Model Difference	Model name is different.			
Product Description	The EUT is a NFC Reader Writer Product. Operation Frequency: 13.56 MHz Antenna Designation: LOOP Antenna More details of EUT technical specification, please refer to the User's Manual.			
Power Source	DC voltage supplied from PC USB port.			
Power Rating	I/P AC 120V/60Hz O/P DC 5V			
Connecting I/O Port(s)	Please refer to the User's Manual			

Note:

1. For a more detailed features description, please refer to the manufacturer's specifications or the User's Manual.

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3.2 DESCRIPTION OF TEST MODES

To investigate the maximum EMI emission characteristics generates from EUT, the test system was pre-scanning tested base on the consideration of following EUT operation mode or test configuration mode which possible have effect on EMI emission level. Each of these EUT operation mode(s) or test configuration mode(s) mentioned above was evaluated respectively.

Pretest Test Mode	Description
Mode 1	TX

Conducted emission test				
Final Test Mode Description				
Mode 1	TX			

Radiated emission test				
Final Test Mode Description				
Mode 1	TX			

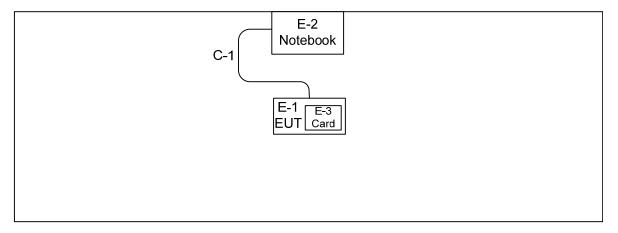
Frequency Stability test				
Final Test Mode Description				
Mode 1	TX			

Antenna Requirement test				
Final Test Mode Description				
Mode 1	TX			

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3.3 BLOCK DIAGRAM SHOWING THE CONFIGURATION OF SYSTEM TESTED



C-1: USB Cable

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3.4 DESCRIPTION OF SUPPORT UNITS

The EUT has been tested as an independent unit together with other necessary accessories or support units. The following support units or accessories were used to form a representative test configuration during the tests.

Item	Equipment	Mfr/Brand	Model/Type No.	FCC ID	Series No.	Note
E-1	NFC Reader Writer Product		TC63CUT021	ORK-TC63CUT021	N/A	EUT
E-2	Notebook	HP	CQ45-m02TX	DOC	N/A	
E-3	Card	N/A	N/A	N/A	N/A	

Item	Shielded Type	Ferrite Core	Length	Note
C-1	YES	NO	1m	

Note:

(1) For detachable type I/O cable should be specified the length in cm in <code>"Length_"</code> column.

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4 EMC EMISSION TEST

4.1 CONDUCTED EMISSION MEASUREMENT

4.1.1 POWER LINE CONDUCTED EMISSION Limits (Frequency Range 150KHz-30MHz)

FREQUENCY (MHz)	Class A	(dBuV)	Class B	Standard	
PREQUENCY (WITZ)	Quasi-peak	Average	Quasi-peak	Average	Stariuaru
0.15 -0.5	79.00	66.00	66 - 56 *	56 - 46 *	CISPR
0.50 -5.0	73.00	60.00	56.00	46.00	CISPR
5.0 -30.0	73.00	60.00	60.00	50.00	CISPR

0.15 -0.5	79.00	66.00	66 - 56 *	56 - 46 *	FCC
0.50 -5.0	73.00	60.00	56.00	46.00	FCC
5.0 -30.0	73.00	60.00	60.00	50.00	FCC

Note:

- (1) The tighter limit applies at the band edges.
- (2) The limit of " * " marked band means the limitation decreases linearly with the logarithm of the frequency in the range.

4.1.2 MEASUREMENT INSTRUMENTS LIST AND SETTING

Item	Kind of Equipment	Manufacturer	Type No.	Serial No.	Last Calibration	Next Calibration
1	LISN	EMCO	3816/2	00052765	May.04.2013	Apr. 25, 2014
2	LISN	R&S	ENV216	100087	Nov.17.2012	Nov.16.2013
3	Test Cable	N/A	C_17	N/A	Mar.28.2013	Mar.15.2014
4	EMI TEST RECEIVER	R&S	ESCS30	826547/02 2	May.04.2013	Apr. 25, 2014
5	50Ω Terminator	SHX	TF2-3G-A	08122902	May.04.2013	Apr. 25, 2014

Remark: "N/A" denotes no model name, serial or calibration specified.

The following table is the setting of the receiver

Receiver Parameters	Setting
Attenuation	10 dB
Start Frequency	0.15 MHz
Stop Frequency	30 MHz
IF Bandwidth	9 kHz

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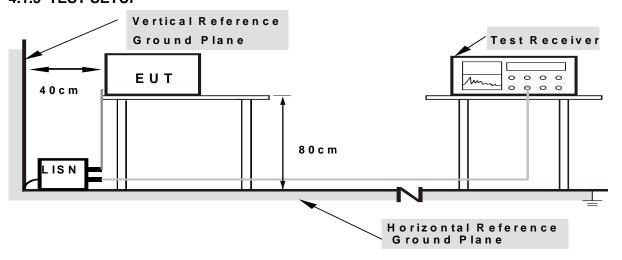
4.1.3 TEST PROCEDURE

- a. The EUT was placed 0.8 meters from the horizontal ground plane with EUT being connected to the power mains through a line impedance stabilization network (LISN). All other support equipments powered from additional LISN(s). The LISN provide 50 Ohm/ 50uH of coupling impedance for the measuring instrument.
- b. Interconnecting cables that hang closer than 40 cm to the ground plane shall be folded back and forth in the center forming a bundle 30 to 40 cm long.
- c. I/O cables that are not connected to a peripheral shall be bundled in the center. The end of the cable may be terminated, if required, using the correct terminating impedance. The overall length shall not exceed 1 m.
- d. LISN at least 80 cm from nearest part of EUT chassis.
- e. For the actual test configuration, please refer to the related Item –EUT Test Photos.

4.1.4 DEVIATION FROM TEST STANDARD

No deviation

4.1.5 TEST SETUP



Note: 1.Support units were connected to second LISN.

2.Both of LISNs (AMN) are 80 cm from EUT and at least 80 from other units and other metal planes

4.1.6 EUT OPERATING CONDITIONS

The EUT was configured for testing in a typical fashion (as a customer would normally use it). The EUT has been programmed to continuously transmit during test. This operating condition was tested and used to collect the included data.

The EUT was programmed to be in continuously transmitting mode.

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4.1.7 TEST RESULTS

Remark

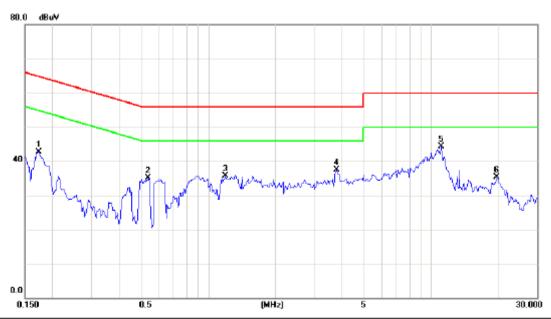
(1) All readings are QP Mode value unless otherwise stated AVG in column of 『Note』. If the QP Mode Measured value compliance with the QP Limits and lower than AVG Limits, the EUT shall be deemed to meet both QP & AVG Limits and then only QP Mode was measured, but AVG Mode didn't perform ∘ In this case, a " * " marked in AVG Mode column of Interference Voltage Measured ∘

(2) Measuring	frequency	range from	150KHz to	30MHz

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E.U.T:	NFC Reader Writer Product	Model Name	TC63CUT021
Temperature :	25 ℃	Relative Humidity:	55%
Pressure :	1010hPa	Test Power :	AC 120V/60Hz
Test Mode :	TX	Phase:	Line

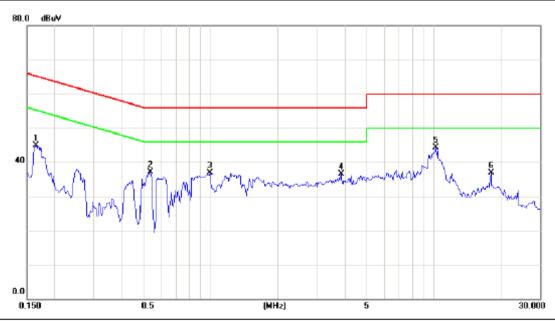


No. Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over		
	MHz	dBuV	dB	dBuV	dBuV	dB	Detector	Comment
1	0.1730	33.06	9.66	42.72	64.82	-22.10	peak	
2	0.5378	25.41	9.70	35.11	56.00	-20.89	peak	
3	1.1906	25.97	9.72	35.69	56.00	-20.31	peak	
4	3.7593	27.70	9.80	37.50	56.00	-18.50	peak	
5 *	11.0796	34.12	10.12	44.24	60.00	-15.76	peak	
6	19.7396	24.87	10.38	35.25	60.00	-24.75	peak	

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E.U.T:	NFC Reader Writer Product	Model Name	TC63CUT021
Temperature :	25 ℃	Relative Humidity:	55%
Pressure :	1010hPa	Test Power :	AC 120V/60Hz
Test Mode :	TX	Phase:	Neutral



	No.	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over		
•			MHz	dBuV	dB	dBuV	dBuV	dB	Detector	Comment
•	1		0.1650	35.34	9.66	45.00	65.21	-20.21	peak	
•	2		0.5350	27.50	9.70	37.20	56.00	-18.80	peak	
•	3		0.9891	27.20	9.71	36.91	56.00	-19.09	peak	
•	4		3.8400	26.79	9.80	36.59	56.00	-19.41	peak	
•	5	*	10.2332	34.12	10.09	44.21	60.00	-15.79	peak	
	6		18.0393	26.59	10.32	36.91	60.00	-23.09	peak	
	5	*	10.2332	34.12	10.09	44.21	60.00	-15.79	peak	

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4.2 RADIATED EMISSION TEST

4.2.1 LIMIT

FCC Part 15.209									
Frequency	Field Streng Limitation		Field Strength Limitation at 3m Measurement Dist						
(MHz)	(uV/m)	Dist	(uV/m)	(dBuV/m)					
0.009 - 0.490	2400 / F(KHz)	300m	10000 * 2400/F(KHz)	20log 2400/F(KHz) + 80					
0.490 - 1.705	24000 / F(KHz)	30m	100 * 24000/F(KHz)	20log 24000/F(KHz) + 40					
1.705 – 30.00	30	30m	100* 30	20log 30 + 40					
30.0 – 88.0	100	3m	100	20log 100					
88.0 – 216.0	150	3m	150	20log 150					
216.0 - 960.0	200	3m	200	20log 200					
Above 960.0	500	3m	500	20log 500					
		FCC P	art 15.225(a)/(b)/(c)						
Frequency	Field Streng Limitation	•	Field Strength Limitation at 3m Measurement Dist						
(MHz)	(uV/m)	Dist	(uV/m)	(dBuV/m)					
13.553 – 13.567	15,848	30 m	15,848*100	124					
13.567 – 13.710	334	30 m	334*100	90.5					
13.110 – 13.410 13.710 – 14.010	106	30 m	106*100	80.5					

Note:

- (1) The tighter limit shall apply at the boundary between two frequency range.
- (2) Limitation expressed in dBuV/m is calculated by 20log Emission Level (uV/m).
- (3) If measurement is made at 3m distance, then F.S Limitation at 3m distance is adjusted by using the formula of $L_{d1} = L_{d2} * (d_2/d_1)^2$.

Example:

F.S Limit at 30m distance is 30uV/m, then F.S Limitation at 3m distance is adjusted as L_{d1} = L_1 = 30uV/m * $(10)^2 = 100 * 30 \text{ uV/m}$ (4) The test result calculated as following:

Measurement Value = Reading Level + Correct Factor

Correct Factor = Insertion Loss + Cable Loss + Attenuator Factor(if use)

Margin Level = Measurement Value - Limit Value

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4.2.2 MEASUREMENT INSTRUMENTS LIST

Item	Kind of Equipment	Manufacturer	Type No.	Serial No.	Last Calibration	Next Calibration	
1	Antenna	Schwarbeck	VULB9160	9160-3232	May.25.2013	Apr. 25, 2014	
2	Amplifier	HP	8447D	2944A09673	May.04.2013	Apr. 25, 2014	
3	Test Receiver	R&S	ESCI	100382	May.04.2013	Apr. 25, 2014	
4	Test Cable	N/A	C-01_CB03	N/A	Jul.01.2012	Jun.30.2013	
5	Antenna	ETS	3115	00075789	May.25.2013	Apr. 25, 2014	
6	Amplifier	Agilent	8449B	3008A02274 May.04.2013		Apr. 25, 2014	
7	Spectrum	Agilent	E4408B	US39240143	Nov.24.2012	Nov. 16.2013	
8	Test Cable	HUBER+SUH NER	C-45	N/A	May.02.2013	Apr. 30, 2014	
9	Controller	СТ	SC100	N/A	N/A	N/A	
10	Horn Antenna	EMCO	3115	9605-4803	May.26.2012	May.25.2013	
11	11 Active Loop Antenna R&S		HFH2-Z2	830749/020	May.04.2013	Apr. 25, 2014	
12	Broad-Band		BBHA 9170	9170319	Oct.13.2012	Oct.12.2013	

Remark:" N/A" denotes no model name, serial no. or calibration specified.

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4.2.3 TEST PROCEDURE

- a. The EUT was placed on the top of a rotating table 0.8 meters above the ground at a 3 meter semi-anechoic chamber. The table was rotated 360 degrees to determine the position of the highest radiation.(below 1GHz)
- b. The EUT was placed on the top of a rotating table 0.8 meters above the ground at a 3 meter fully-anechoic chamber. The table was rotated 360 degrees to determine the position of the highest radiation.(above 1GHz)
- c. The height of the equipment or of the substitution antenna shall be 0.8 m; the height of the test antenna shall vary between 1 m to 4 m. Both horizontal and vertical polarizations of the antenna are set to make the measurement.
- d. The initial step in collecting conducted emission data is a spectrum analyzer peak detector mode pre-scanning the measurement frequency range. Significant peaks are then marked and then Quasi Peak detector mode re-measured.
- e. If the Peak Mode measured value compliance with and lower than Quasi Peak Mode Limit, the EUT shall be deemed to meet QP Limits and then no additional QP Mode measurement performed.
- f. For the actual test configuration, please refer to the related Item –EUT Test Photos.

NOTE: (FCC PART 15.209)

- a. Reading in which marked as QP or Peak means measurements by using are Quasi-Peak Mode with Detector BW=120 kHz.
- b. All readings are Peak unless otherwise stated QP in column of Note. Peak denotes that the Peak reading compliance with the QP Limits and then QP Mode measurement didn't perform.

NOTE: (FCC PART 15.225)

- a. Spectrum Setting:
 - 9 KHz 150 KHz, RBW= 200Hz, VBW=200Hz, Sweep time = 200 ms. 150 K Hz – 30 MHz, RBW= 10 KHz, VBW=10 KHz, Sweep time = 200 ms. 30 MHz – 1000 MHz, RBW= 100KHz, VBW=100KHz, Sweep time = 200 ms.
- b. All readings are Peak unless otherwise stated QP in column of Note. Peak denotes that the Peak reading compliance with the QP Limits and then QP Mode measurement didn't perform.
- c. The Log-Bicon Antenna will use to test frequency range from 30MHz to 1000MHz and the Loop Antenna will use to test frequency below 30MHz.

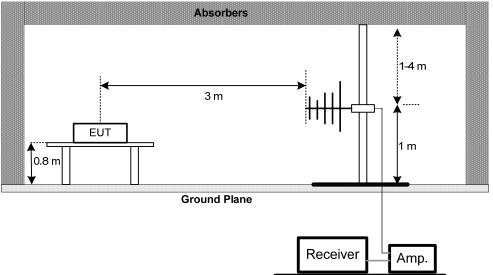
4.2.4 DEVIATION FROM TEST STANDARD

No deviation

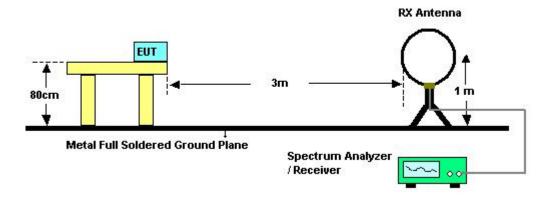


4.2.5 TEST SETUP

(A) Radiated Emission Test Set-Up Frequency Below 1 GHz



(B) For radiated emissions below 30MHz



4.2.6 EUT OPERATING CONDITIONS

The EUT tested system was configured as the statements of **4.1.6** Unless otherwise a special operating condition is specified in the follows during the testing.

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4.2.7 TEST RESULTS (BELOW 30MHZ) - FCC PART 15.209

EUT:	NFC Reader Writer Product	Model Name	TC63CUT021
Temperature:	25 ℃	Relative Humidity:	58 %
Pressure:	1010 hPa	Test Voltage :	AC 120V/60Hz
Test Mode :	TX MODE		

Freq.	Ant.	Reading(RA)	Corr.Factor(CF)	Measured(FS)	Limits(QP)	Margin	Note
(MHz)	0°/90°	(dBuV)	(dB)	(dBuV/m)	(dBuV/m)	(dB)	NOIC
0.0401	0°	21.21	23.03	44.24	115.54	-71.30	AVG
0.0401	0°	34.98	23.76	58.74	135.54	-76.80	PK
0.3345	0°	19.14	20.20	39.34	97.12	-57.78	AVG
0.3345	0°	35.01	21.90	56.91	117.12	-60.21	PK
0.4785	0°	20.18	19.85	40.03	94.01	-53.97	AVG
0.4785	0°	33.65	20.14	53.79	114.01	-60.21	PK
2.8685	0°	28.71	18.98	47.69	69.54	-21.85	QP
4.6782	0°	27.58	18.46	46.04	69.54	-23.50	QP
5.8541	0°	29.65	18.13	47.78	69.54	-21.76	QP

Freq.	Ant.	Reading(RA)	Corr.Factor(CF)	Measured(FS)	Limits(QP)	Margin	Note
(MHz)	0°/90°	(dBuV)	(dB)	(dBuV/m)	(dBuV/m)	(dB)	Note
0.0747	90°	18.56	21.91	40.47	110.14	-69.67	AVG
0.0747	90°	28.68	22.25	50.93	130.14	-79.21	PK
0.3898	90°	20.58	20.06	40.64	95.79	-55.14	AVG
0.3898	90°	33.96	21.19	55.15	115.79	-60.64	PK
2.7347	90°	27.88	19.06	46.94	69.54	-22.60	QP
3.8715	90°	29.46	18.99	48.45	69.54	-21.09	QP
5.7295	90°	26.58	18.14	44.72	69.54	-24.82	QP
7.8524	90°	25.61	17.97	43.58	69.54	-25.96	QP

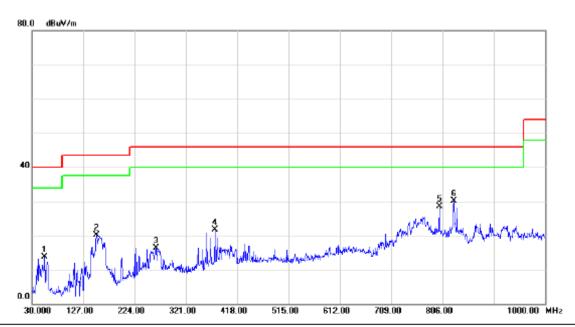
Remark

- (1) The amplitude of spurious emissions which are attenuated by more than 20 dB below the permissible value has no need to be reported \circ
- (2) Distance extrapolation factor = 40 log (specific distance / test distance) (dB); •
- (3) Limit line = specific limits (dBuV) + distance extrapolation factor. •

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4.2.8 TEST RESULTS - (30-1000MHZ) - FCC PART 15.209

E.U.T	NFC Reader Writer Product	Model Name	TC63CUT021
Temperature	26°C	Relative Humidity	60%
Test Voltage	AC 120V/60Hz	Polarization	Vertical
Test Mode	TX		

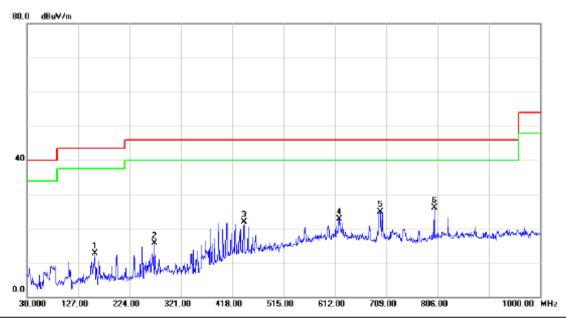


	No.	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over		
_			MHz	dBuV	dB	dBuV/m	dBuV/m	dB	Detector	Comment
_	1		54.2500	31.36	-17.63	13.73	40.00	-26.27	peak	
_	2		152.2200	37.94	-17.86	20.08	43.50	-23.42	peak	
_	3		264.7400	30.39	-14.11	16.28	46.00	-29.72	peak	
_	4		376.2900	32.31	-10.63	21.68	46.00	-24.32	peak	
_	5		800.1800	32.19	-3.62	28.57	46.00	-17.43	peak	
_	6	*	827.3400	33.30	-3.14	30.16	46.00	-15.84	peak	
_										·

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E.U.T	NFC Reader Writer Product	Model Name	TC63CUT021
Temperature	26°C	Relative Humidity	60%
Test Voltage	AC 120V/60Hz	Polarization	Horizontal
Test Mode	TX		



No.	Mk	. Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over		
		MHz	dBuV	dB	dBuV/m	dBuV/m	dB	Detector	Comment
1		159.0100	30.58	-17.96	12.62	43.50	-30.88	peak	
2		271.5300	29.40	-13.72	15.68	46.00	-30.32	peak	
3		440.3100	31.00	-9.17	21.83	46.00	-24.17	peak	
4		620.7300	27.91	-5.16	22.75	46.00	-23.25	peak	
5		697.3600	29.59	-4.67	24.92	46.00	-21.08	peak	
6	*	800.1800	29.65	-3.62	26.03	46.00	-19.97	peak	

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4.2.9 TEST RESULTS- FCC PART 15.225

E.U.T	NFC Reader Writer Product	Model Name	TC63CUT021
Temperature	26°C	Relative Humidity	60%
Test Voltage	AC 120V/60Hz		
Test Mode	TX		

Freq.	Ant.	Reading(RA)	Corr.Factor(CF)	Measured(FS)	Limits(QP)	Margin	Note
(MHz)	0°/90°	(dBuV)	(dB)	(dBuV/m)	(dBuV/m)	(dB)	Note
13.560	0°	44.53	10.99	55.52	124.00	-68.48	
27.020	0°	20.42	9.33	29.75	69.54	-39.79	

Freq.	Ant.	Reading(RA)	Corr.Factor(CF)	Measured(FS)	Limits(QP)	Margin	Note
(MHz)	0°/90°	(dBuV)	(dB)	(dBuV/m)	(dBuV/m)	(dB)	NOIE
13.560	90°	39.02	10.99	50.01	124.00	-73.99	
27.020	90°	17.25	9.33	26.58	69.54	-42.96	

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4.3 FREQUENCY STABILITY MEASUREMENT

4.3.1 LIMIT

FCC Part 15.225(e)

The frequency tolerance of the carrier signal shall be maintained within +/-0.01% of the operating frequency over a temperature variation of - 20 degrees to + 50 degrees C at normal supply voltage, and for a variation in the primary supply voltage from 85% to 115% of the rated supply voltage at a temperature of 20 degrees C.

For battery operated equipment, the equipment tests shall be performed using a new battery.

4.3.2 MEASUREMENT INSTRUMENTS LIST

Item	Kind of Equipment	Manufacturer	Type No.	Serial No.	Last Calibration	Next Calibration
1	Spectrum Analyzer	R&S	FSP_40	100185	Nov. 17.2012	Nov. 16.2013

Remark:" N/A" denotes no model name, serial no. or calibration specified.

4.3.3 TEST PROCEDURE

- a. The equipment under test was connected to an external AC power supply and the RF output was connected to a frequency counter via feed through attenuators. The EUT was placed inside the temperature chamber.
 - After the temperature stabilized for approximately 20 minutes, the frequency of the output signal was recorded from the counter.
- b. At room temperature (25±5°C), an external variable AC power supply was connected to the EUT. The frequency of the transmitter was measured for 115%, 100% and 85% of the nominal operating input voltage.

4.3.4 DEVIATION FROM TEST STANDARD

No deviation

4.3.5 EUT OPERATING CONDITIONS

The EUT tested system was configured as the statements of **4.1.6** Unless otherwise a special operating condition is specified in the follows during the testing.

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Neutron Engineering Inc._____

4.3.6 TEST RESULTS

E.U.T	NFC Reader Writer Product	Model Name	TC63CUT021
Temperature	26°C	Relative Humidity	60%
Test Voltage	AC 120V/60Hz		
Test Mode	TX		

Frequency Stability Versus Environmental Temperature						
	Temperature (°C)	Voltage (AC)	Frequency (MHz)	Frequency Error (kHz)	Limit (kHz)	Result
	20	120V	13.5600			
0 min	50	120V	13.5601	0.0001	+/- 1.356	PASS
	-20	120V	13.5612	0.0012	+/- 1.356	PASS
2 min	50	120V	13.5623	0.0023	+/- 1.356	PASS
	-20	120V	13.5608	0.0008	+/- 1.356	PASS
5 min	50	120V	13.5606	0.0006	+/- 1.356	PASS
	-20	120V	13.5617	0.0017	+/- 1.356	PASS
10 min	50	120V	13.5613	0.0013	+/- 1.356	PASS
	-20	120V	13.5602	0.0002	+/- 1.356	PASS

Fuequency Stability Versus Input Voltage							
Temperature (°C)	Voltage (AC)		Frequency (MHz)	Frequency Error (kHz)	Limit (kHz)	Result	
20	V-nom	120V	13.5600				
20	V-min	118V	13.5612	0.012	+/- 1.356	PASS	
20	V-max	132V	13.5623	0.023	+/- 1.356	PASS	

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5. 20dB SPECTRUM BANDWIDTH MEASUREMENT

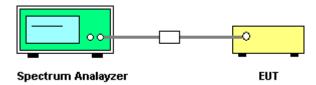
5.1. LIMIT OF 20dB BANDWIDTH MEASUREMENT

The 20dB bandwidth shall be specified in operating frequency band.

5.2.TEST PROCEDURES

The bandwidth of the fundamental frequency was measured by spectrum analyzer with 9kHz RBW and 9kHz VBW. The 20dB bandwidth is defined as the total spectrum the power of which is higher than peak power minus 20dB.

5.3. TEST SETUP LAYOUT



5.4. TEST DEVIATION

There is no deviation with the original standard.

5.5. EUT OPERATION DURING TEST

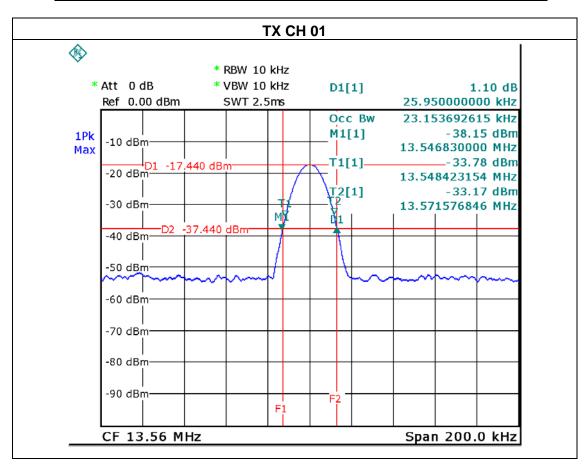
The EUT was programmed to be in continuously transmitting mode.

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5.6. TEST RESULT

E.U.T	NFC Reader Writer Product	Model Name	TC63CUT021
Temperature	26°C	Relative Humidity	60%
Test Voltage	AC 120V/60Hz		
Test Mode	TX		

Frequency	20 dBc Bandwidth	99% OBW	Result	
(MHz)	(KHz)	(KHz)	result	
13.56	25.95	23.15	PASS	



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6. EUT TEST PHOTO

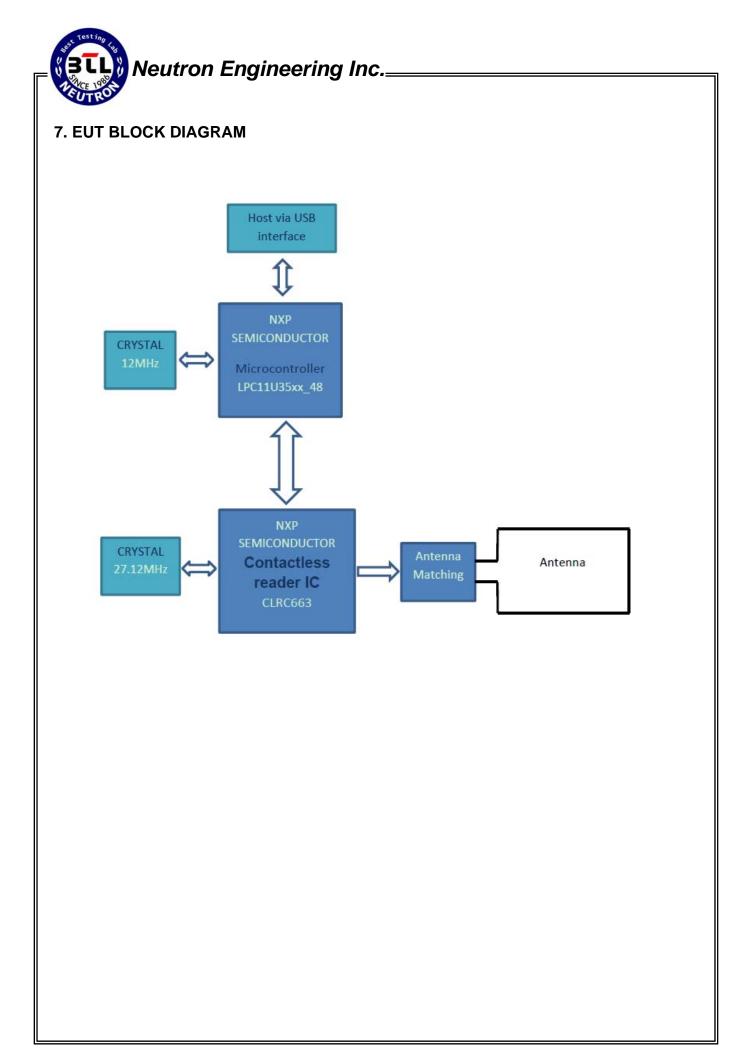
Radiated emission test photos

TX





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